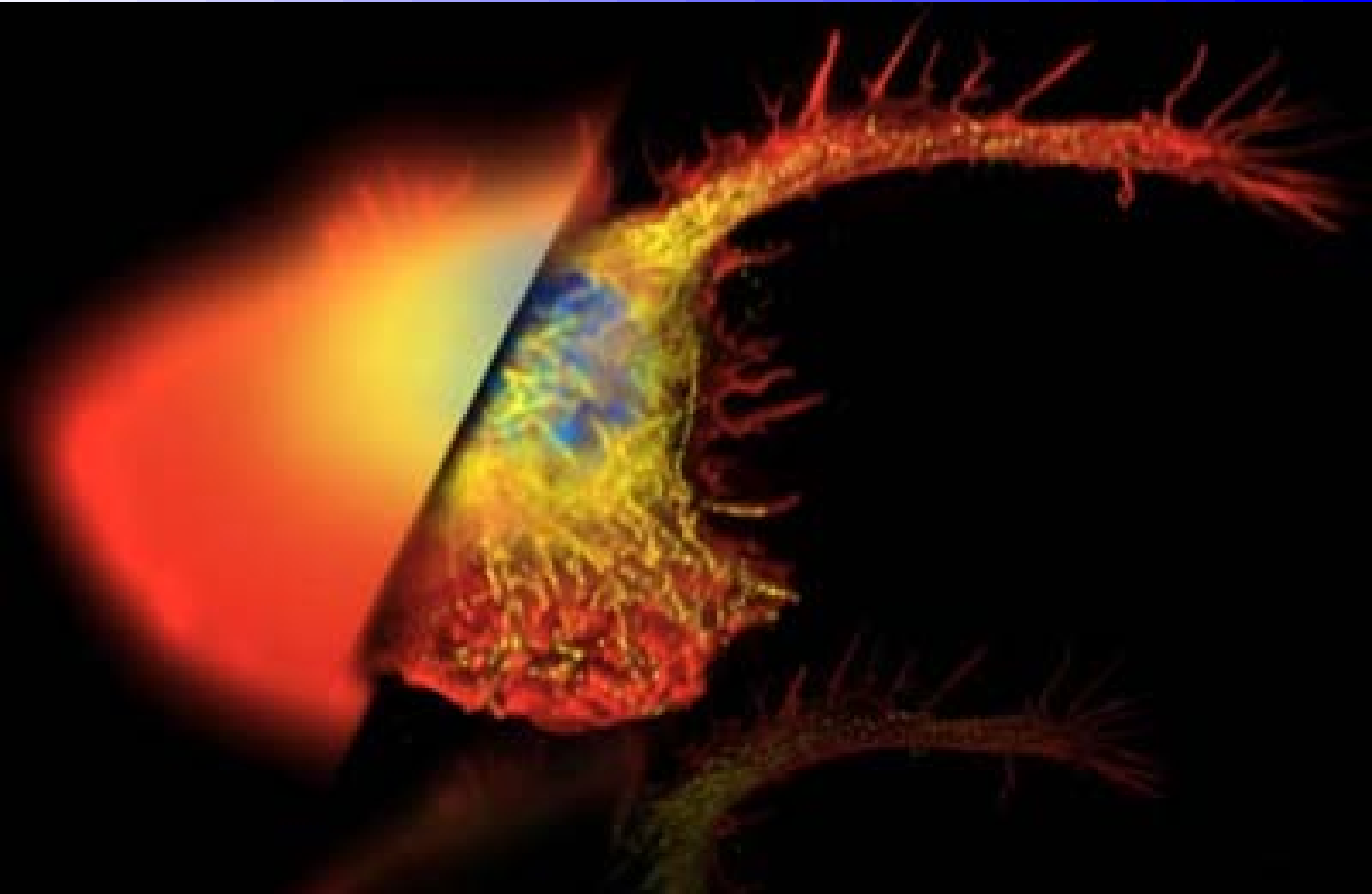
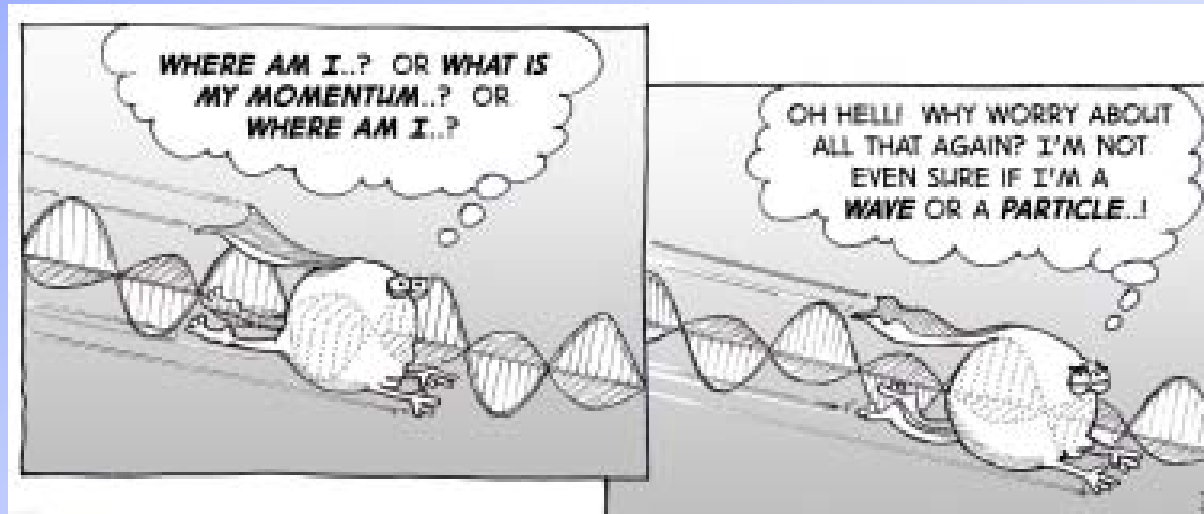


# Deconvolution



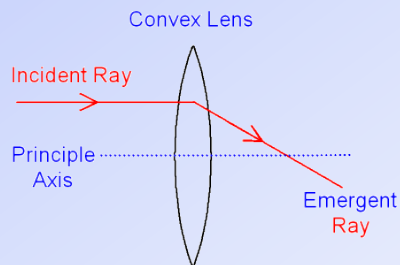
The beginning: Let there be light



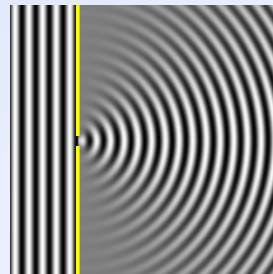
## A photon is a wave... and a particle

In microscopy, we exploit mainly wave characteristics:

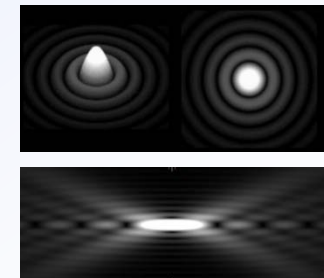
### Refraction



### Diffraction

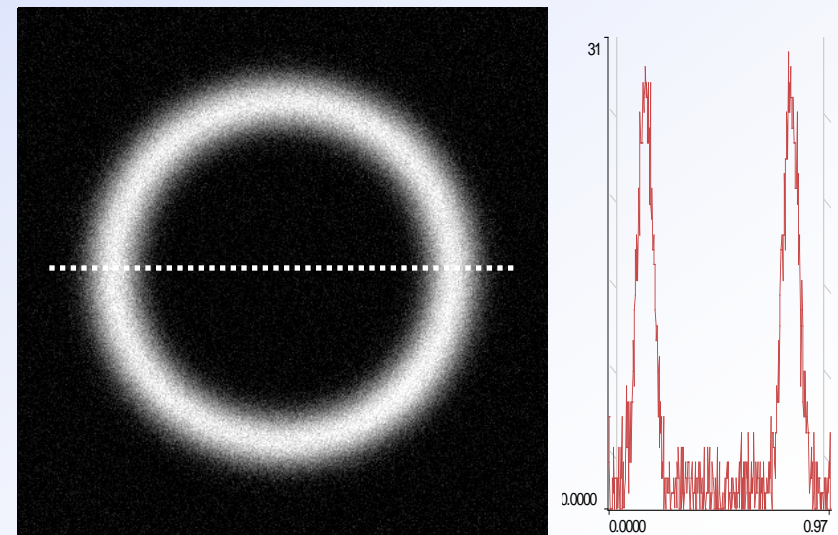
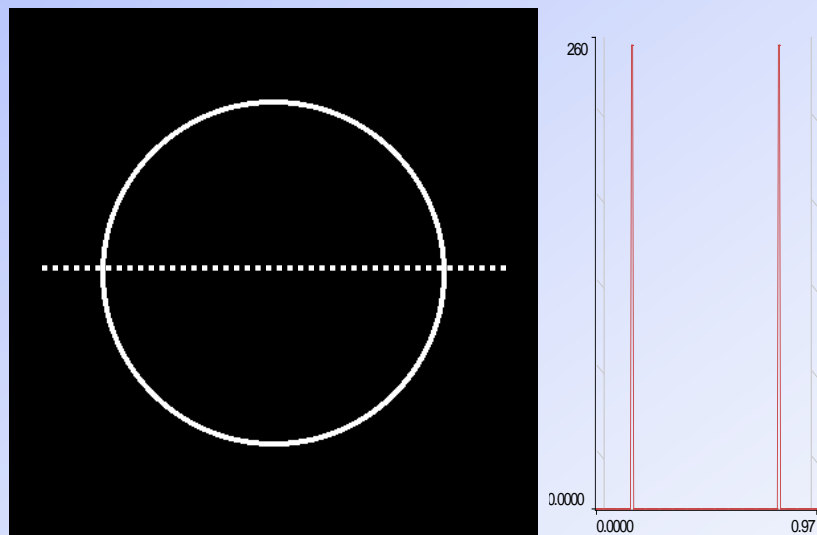


### Interference

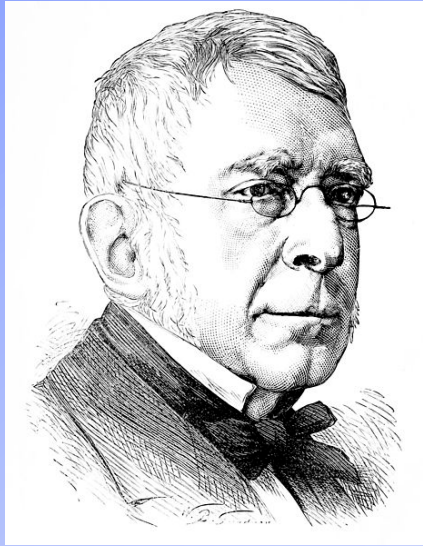


## I Image Formation: From an object to an image

- Microscopes read out object information and display it visually.
- This transfer is always partial. No method works without loss of information
- Image quality is limited (mostly) by the microscope's resolving power and image noise.
- The resolving power can be limited by aberration or diffraction



# The Airy pattern

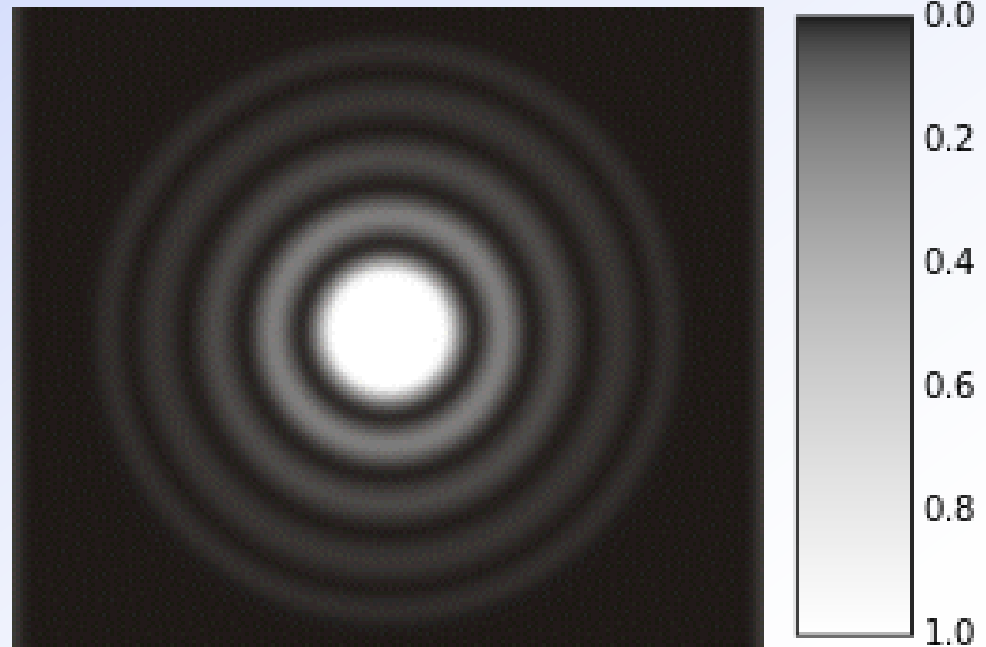


*„...the star is then seen (in favourable circumstances of tranquil atmosphere, uniform temperature, &c.) as a perfectly round, well-defined planetary disc, surrounded by two, three, or more alternately dark and bright rings, which, if examined attentively, are seen to be slightly coloured at their borders...”*

*George Biddell Airy*

1801 - 1892

**Light from a point source passing a circular apperture (e.g. a lens) produces a disc surrounded by concentric rings.**



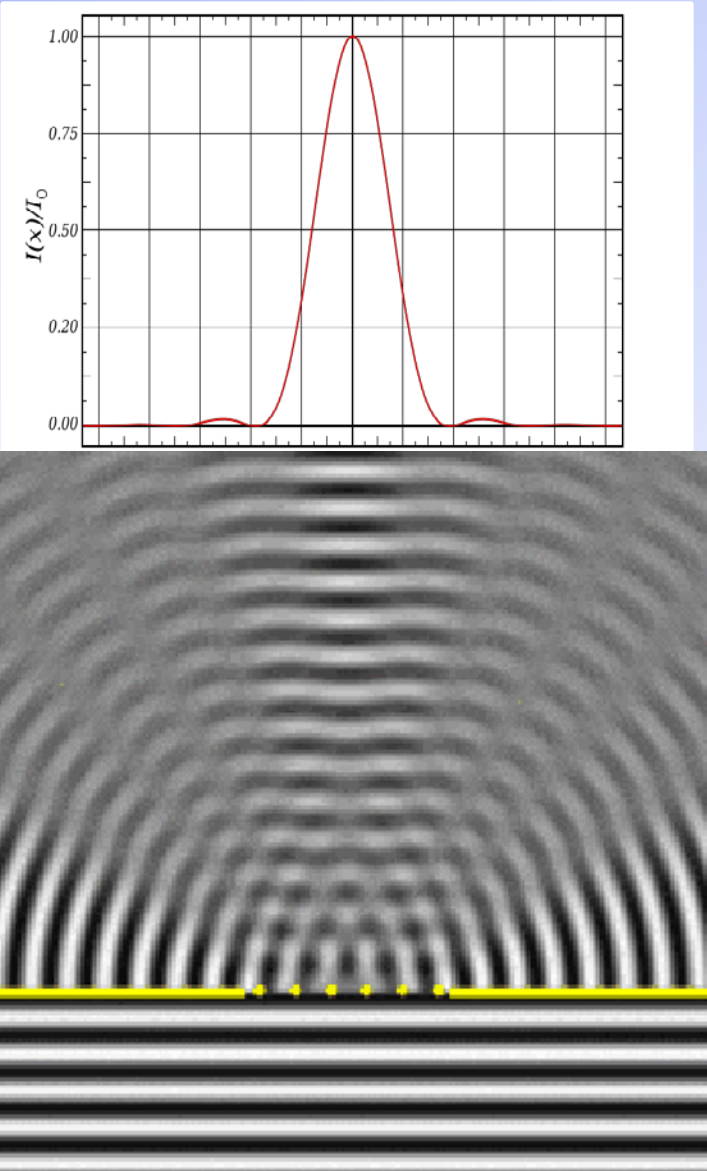
Huygens' principle



*Christiaan Huygens*  
1629 - 1695



*Siméon Poisson*  
1781 - 1840

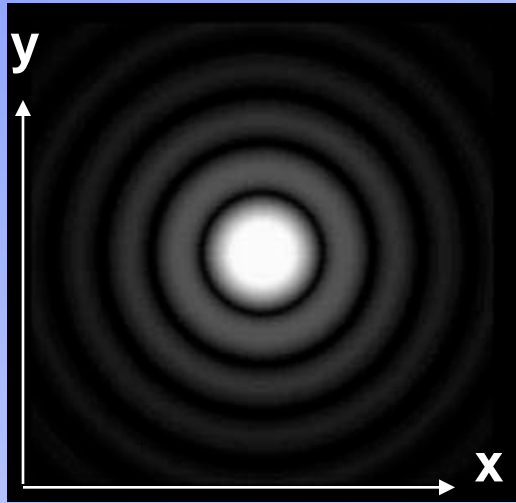


*Augustin-Jean Fresnel*  
1788 - 1827

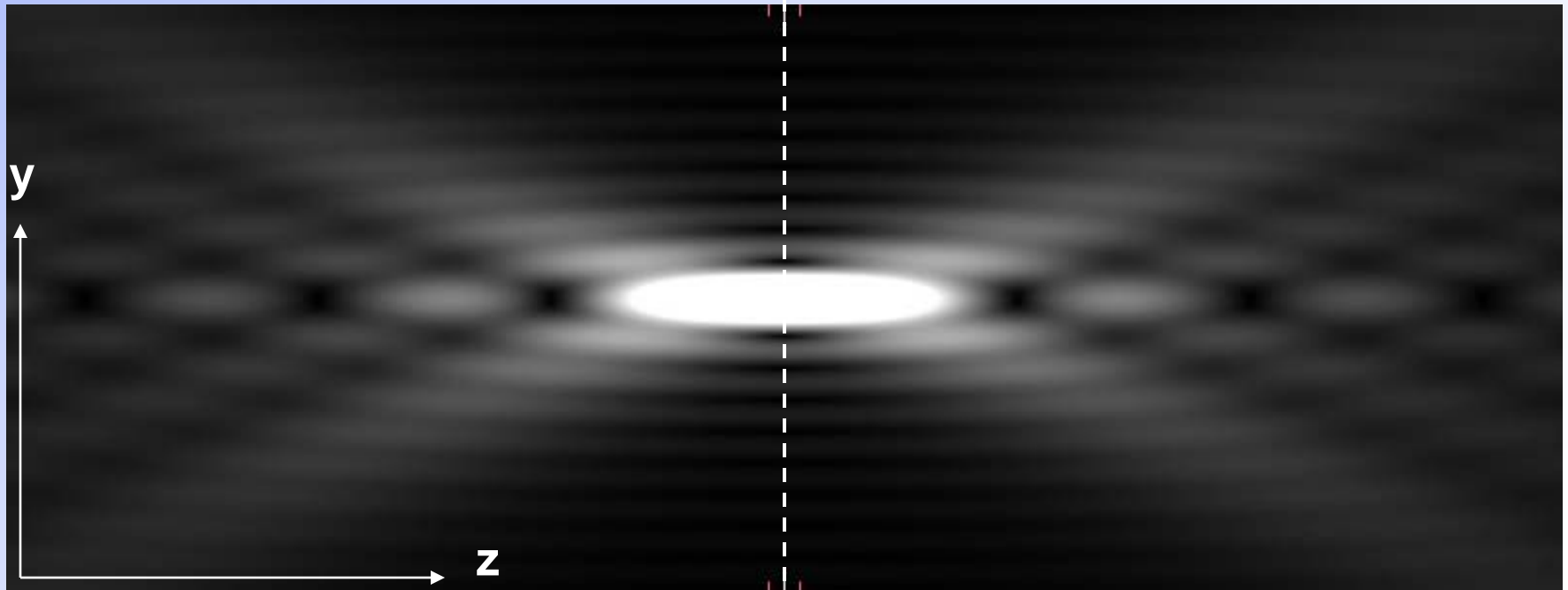


*Francois Arago*  
1786 - 1853

## The point spread function (PSF)

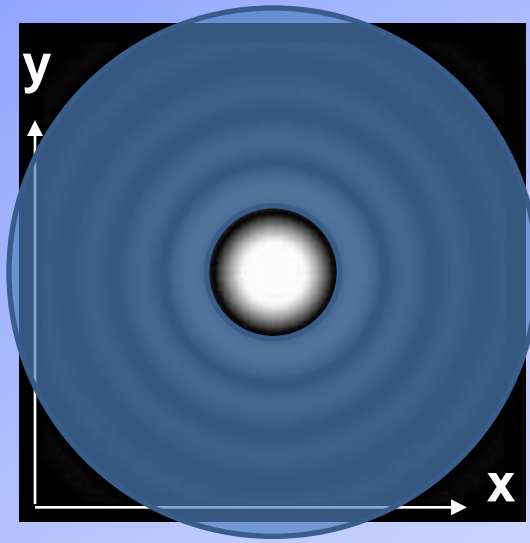


- The PSF is the image of a point source
- It is defined by aberration and diffraction
- The PSF is elongated along the z axis
- Its size limits the microscope's resolving power in x/y and in z

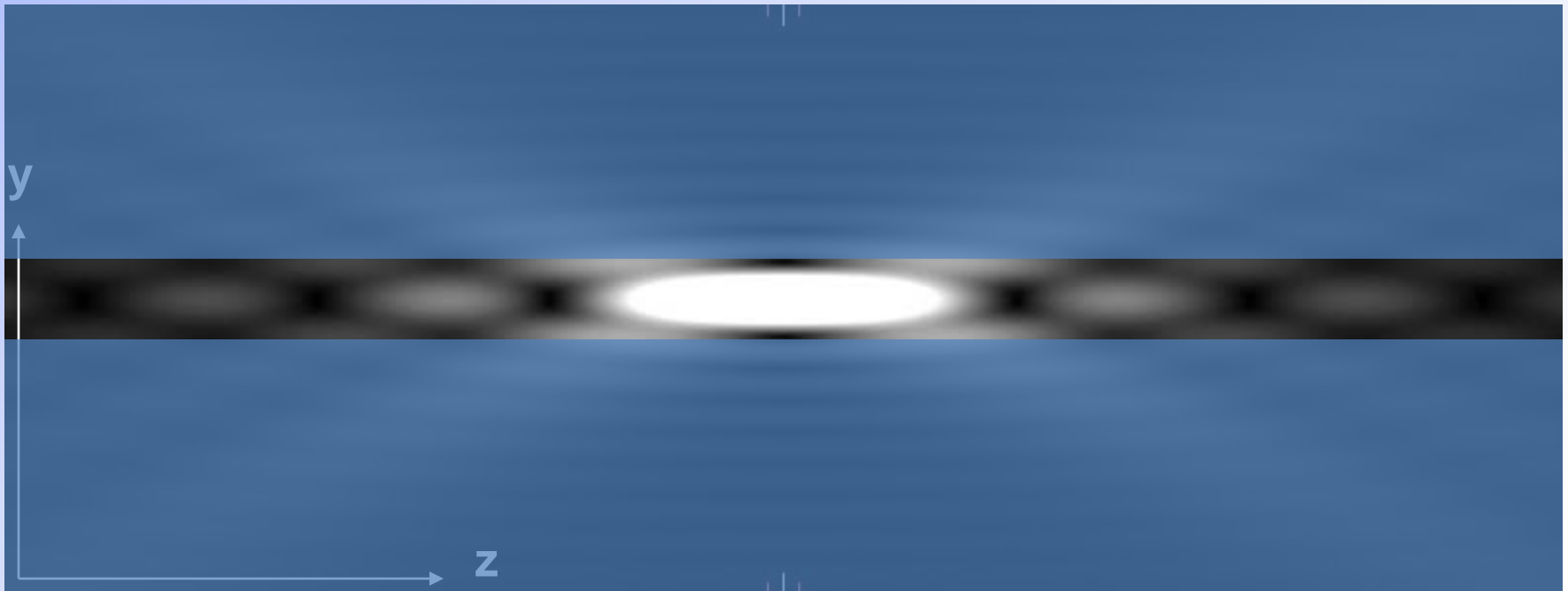


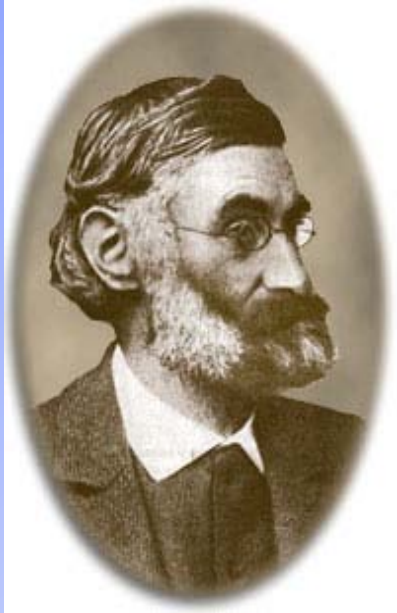


## The confocal pinhole



- The pinhole cuts off most out-of-focus light
- Its size is variable. It is usually set to one Airy unit (1AU)
- 1AU corresponds to the size of the Airy disc.
- This size depends on a number of factors





Ernst Abbe  
1840 - 1905

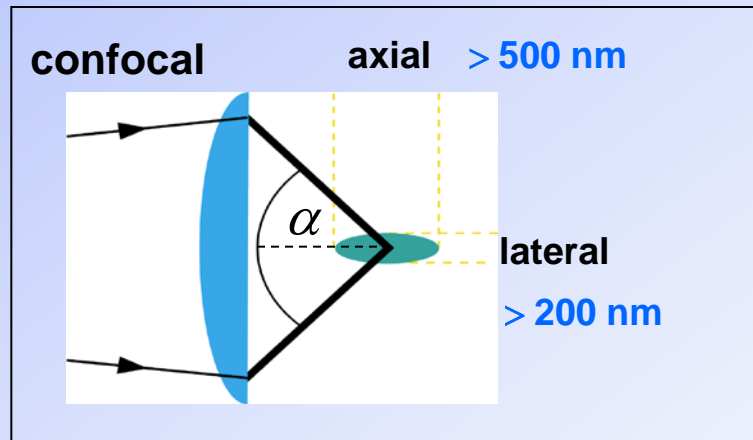
## Equation of Abbe

lateral

$$\Delta x \approx \frac{0,61\lambda}{n \sin \alpha} = \frac{0,61\lambda}{NA}$$

axial

$$\Delta z \approx \frac{\lambda}{2n \sin \alpha} = \frac{2\lambda n}{(NA)^2}$$



$\Delta x$  = resolution

$\lambda$  = wavelength

$n$  = refractive index of medium

$\alpha$  = opening angle of the objective

$NA$  = Numerical Aperture

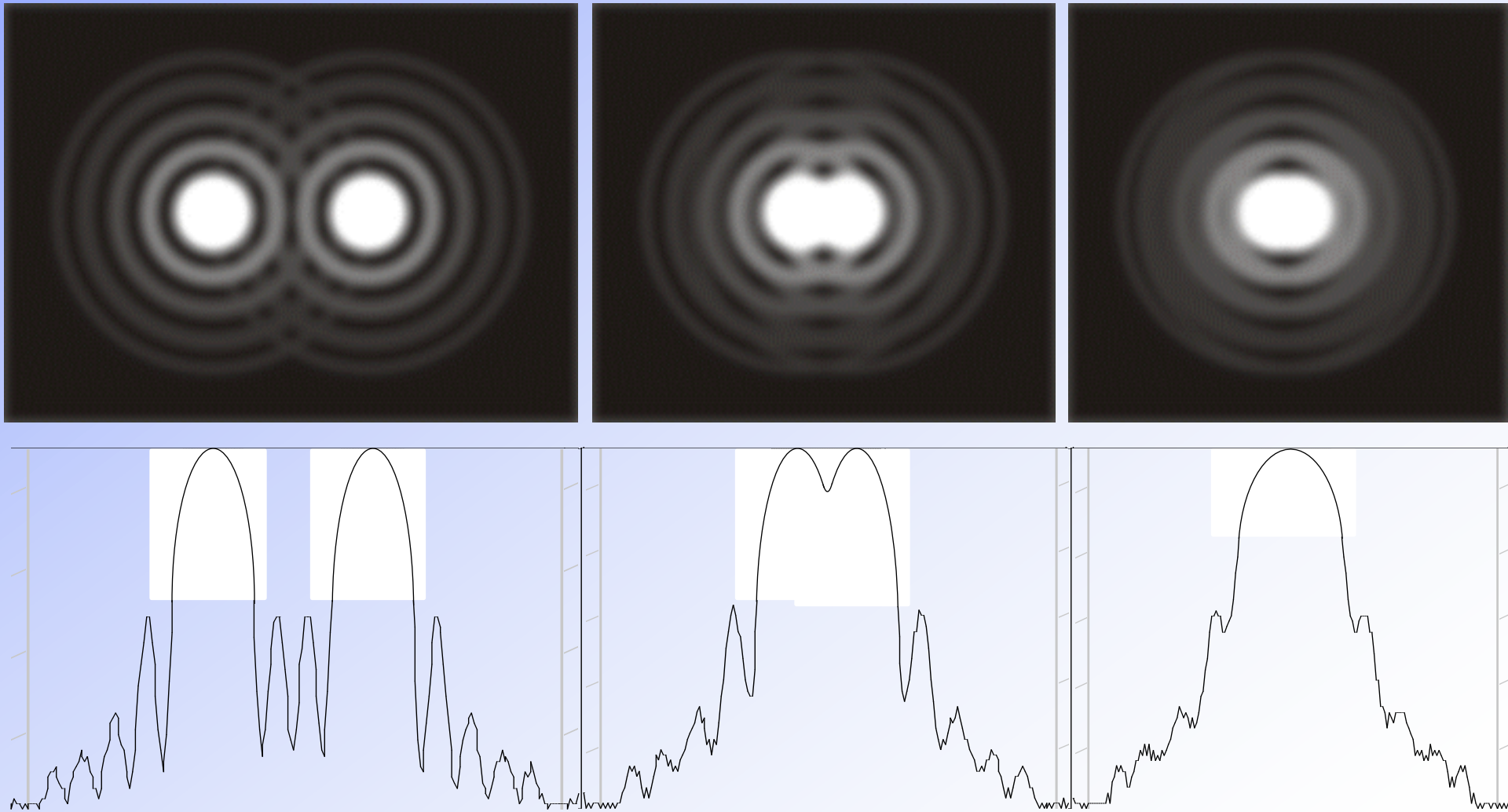
### → improving resolution:

- Immersion medium with high refractive index (oil)
- Objectives with a high refractive index
- Lowering of the wavelength



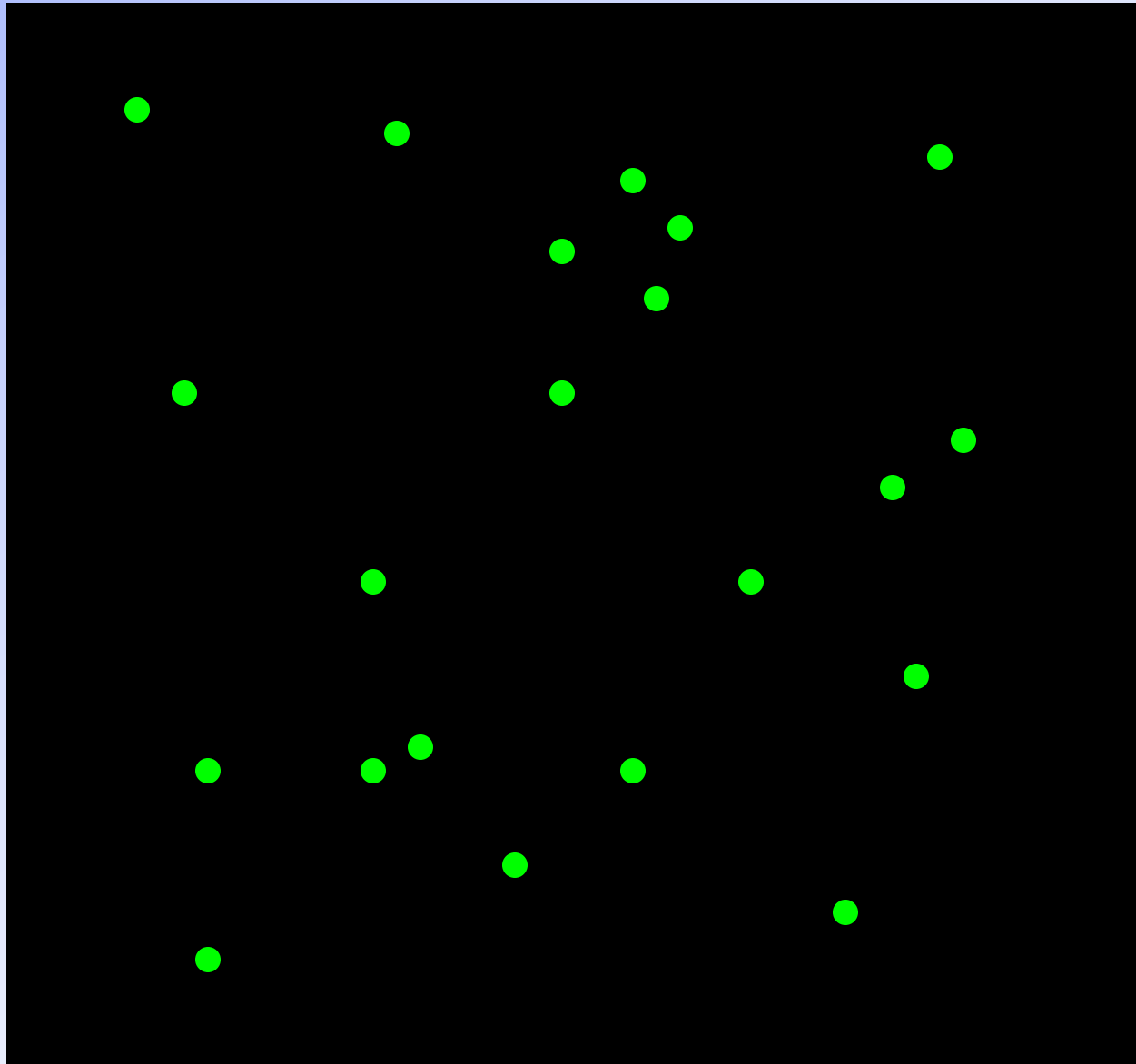
## Resolution: the Rayleigh criterion

Two points can be resolved at a minimum distance corresponding to the distance between the center of the Airy pattern and the first minimum



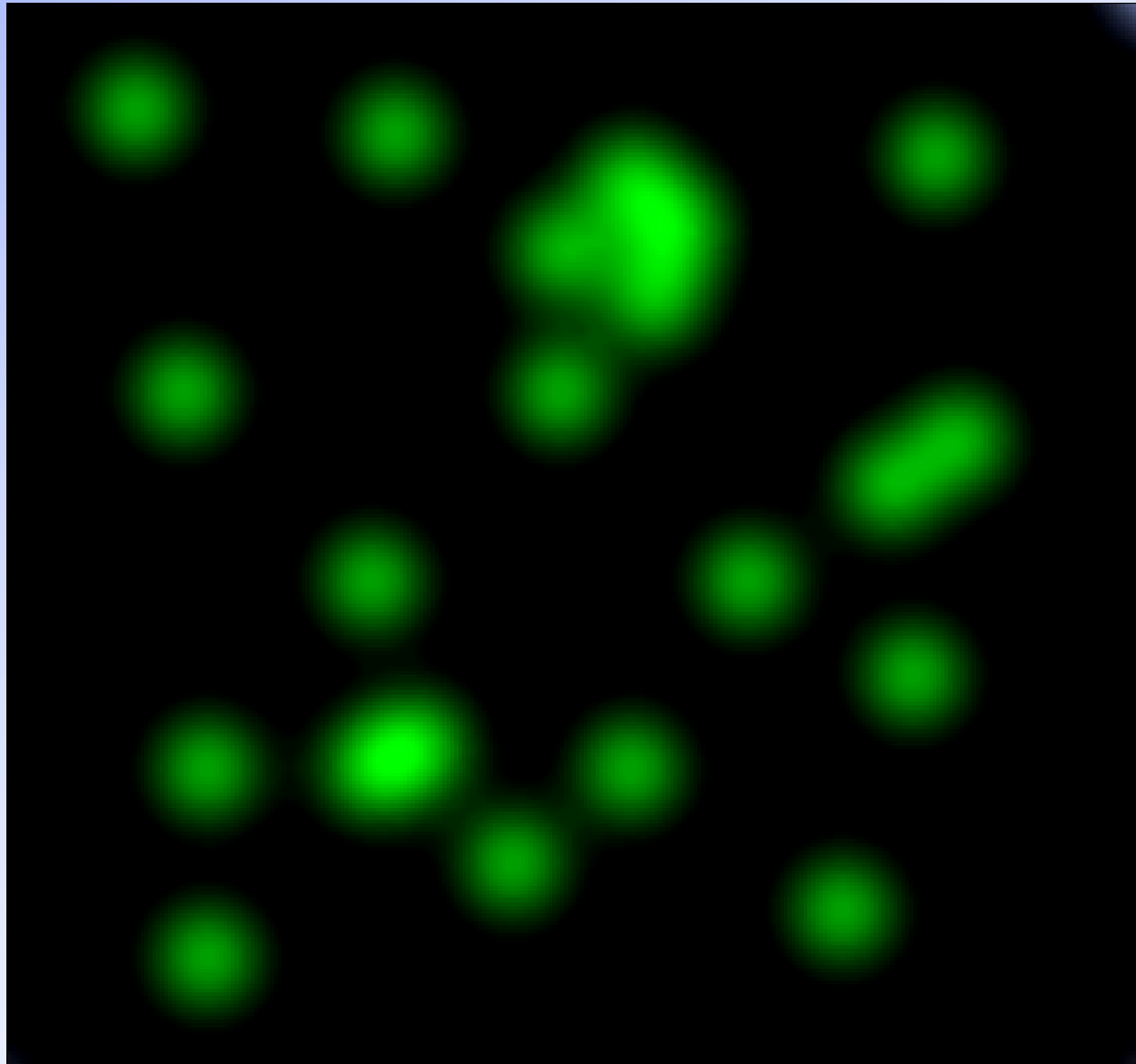
**In the final image,  
every point source  
is replaced by the  
microscope's  
point spread  
function (PSF)**

**Image formation is  
a convolution of  
object data with  
the microscope's  
PSF.**



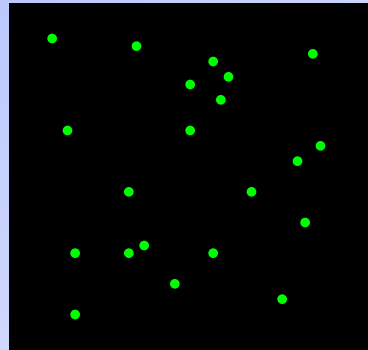
**In the final image,  
every point source  
is replaced by the  
microscope's  
point spread  
function (PSF)**

**Image formation is  
a convolution of  
object data with  
the microscope's  
PSF.**

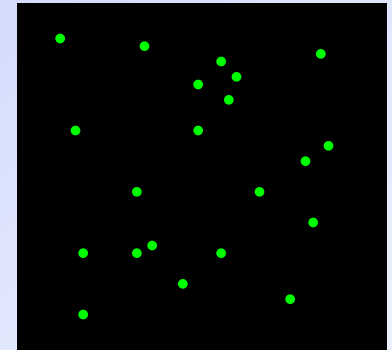


What you want:

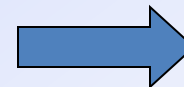
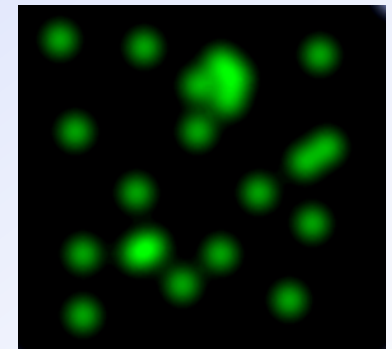
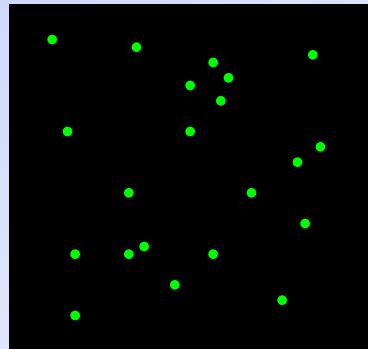
*object*



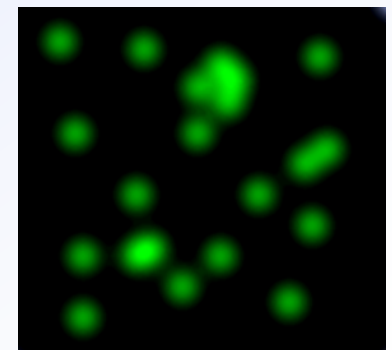
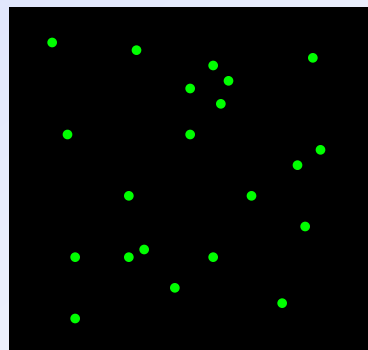
*image*



What you get:



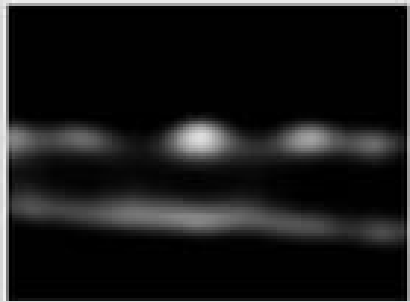
What you need:



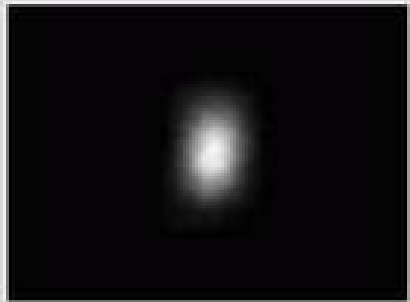
## Convolution in position space

Per pixel:  $x*y$  operations

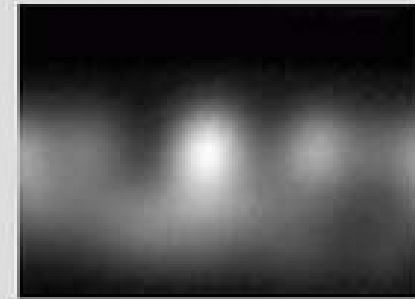
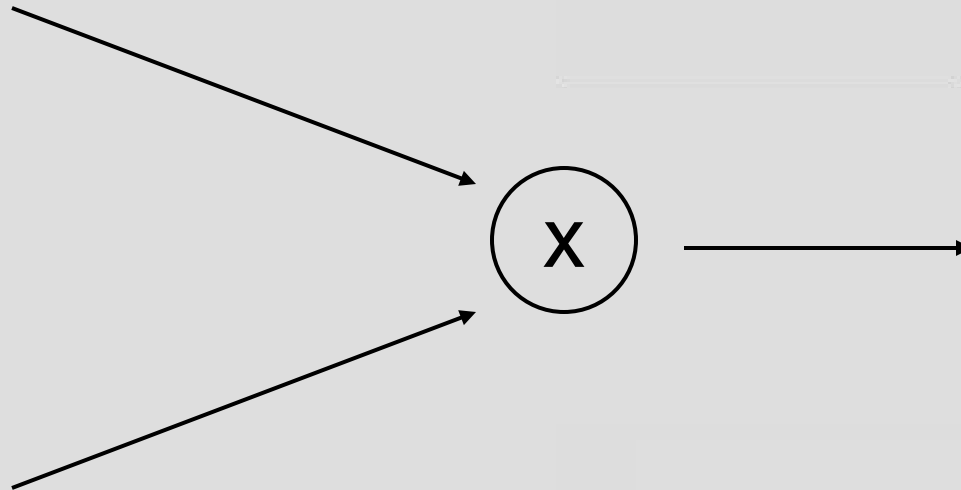
Per image:  $(x*y)^2$  operations



Object



PSF

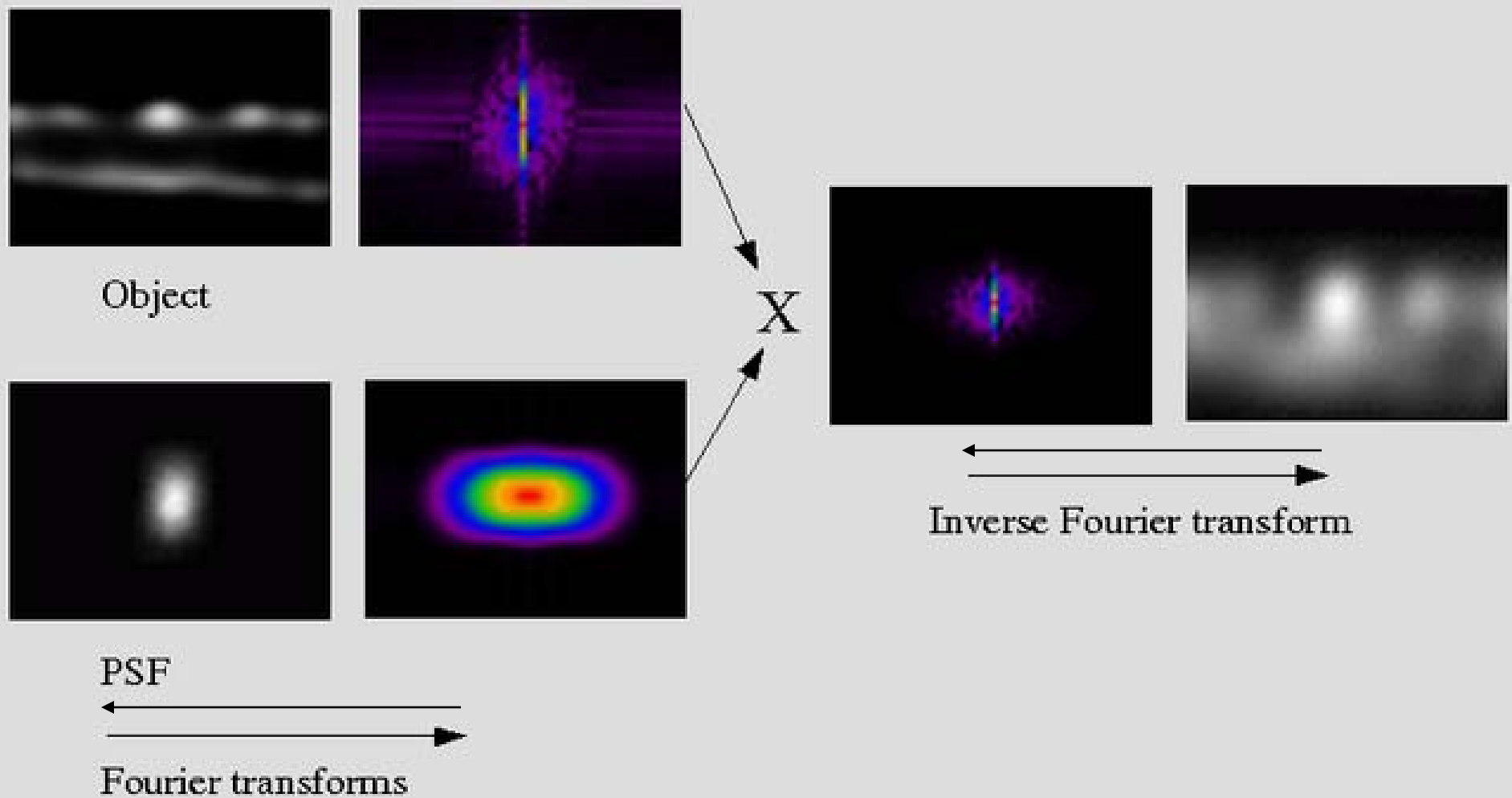


Image

# Convolution in frequency space

~~Per pixel:  $x \cdot y$  operations~~  
~~Per image:  $(x \cdot y)^2$  operations~~

Per pixel: 1 operation  
Per image:  $x \cdot y$  operations

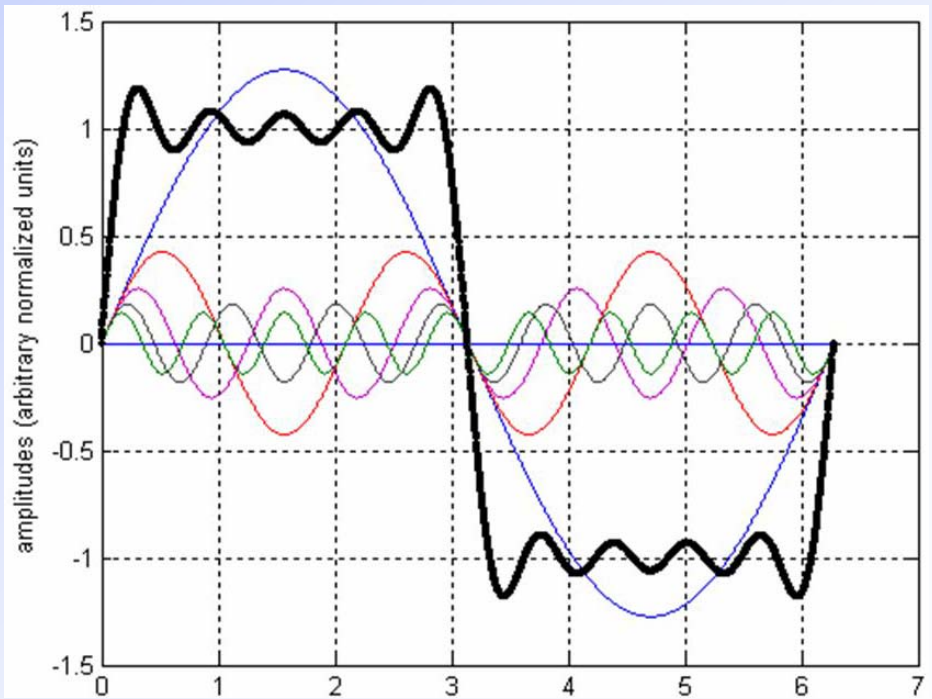
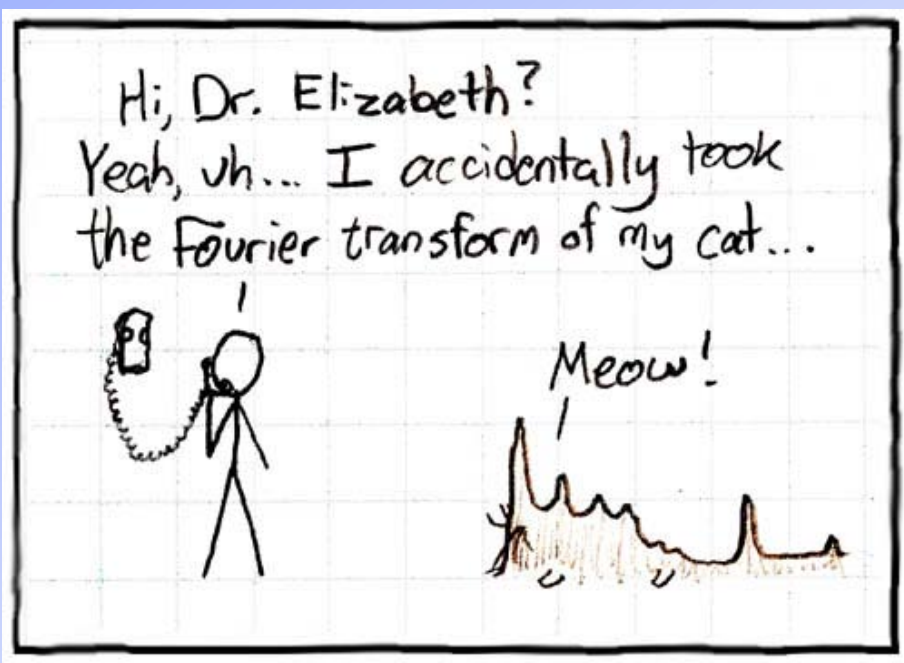




# Convolution in position space

~~Per pixel:  $x \cdot y$  operations~~  
~~Per image:  $(x \cdot y)^2$  operations~~

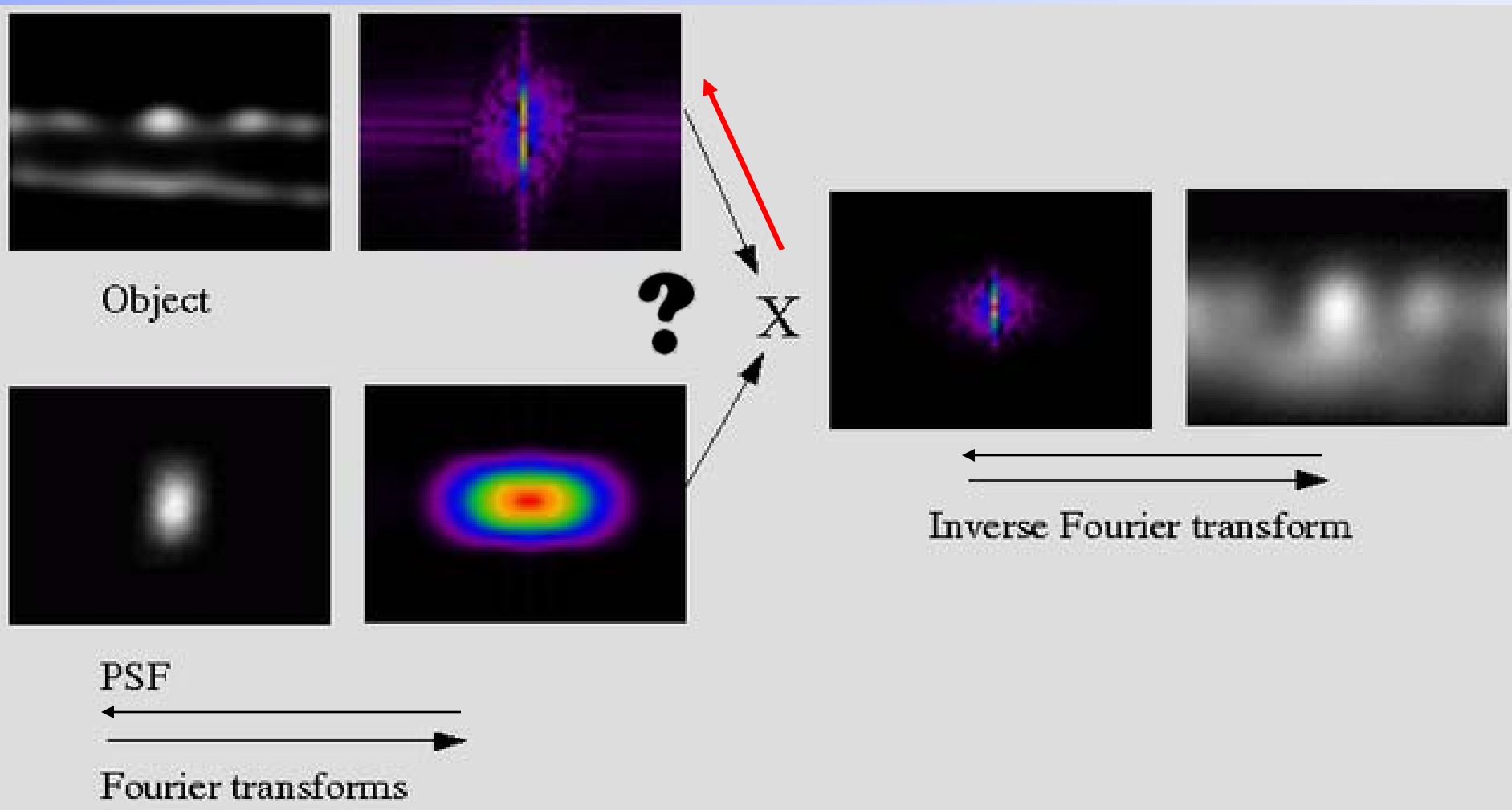
Per pixel: 1 operation  
Per image:  $x \cdot y$  operations



Convolution in frequency space: linear deconvolution

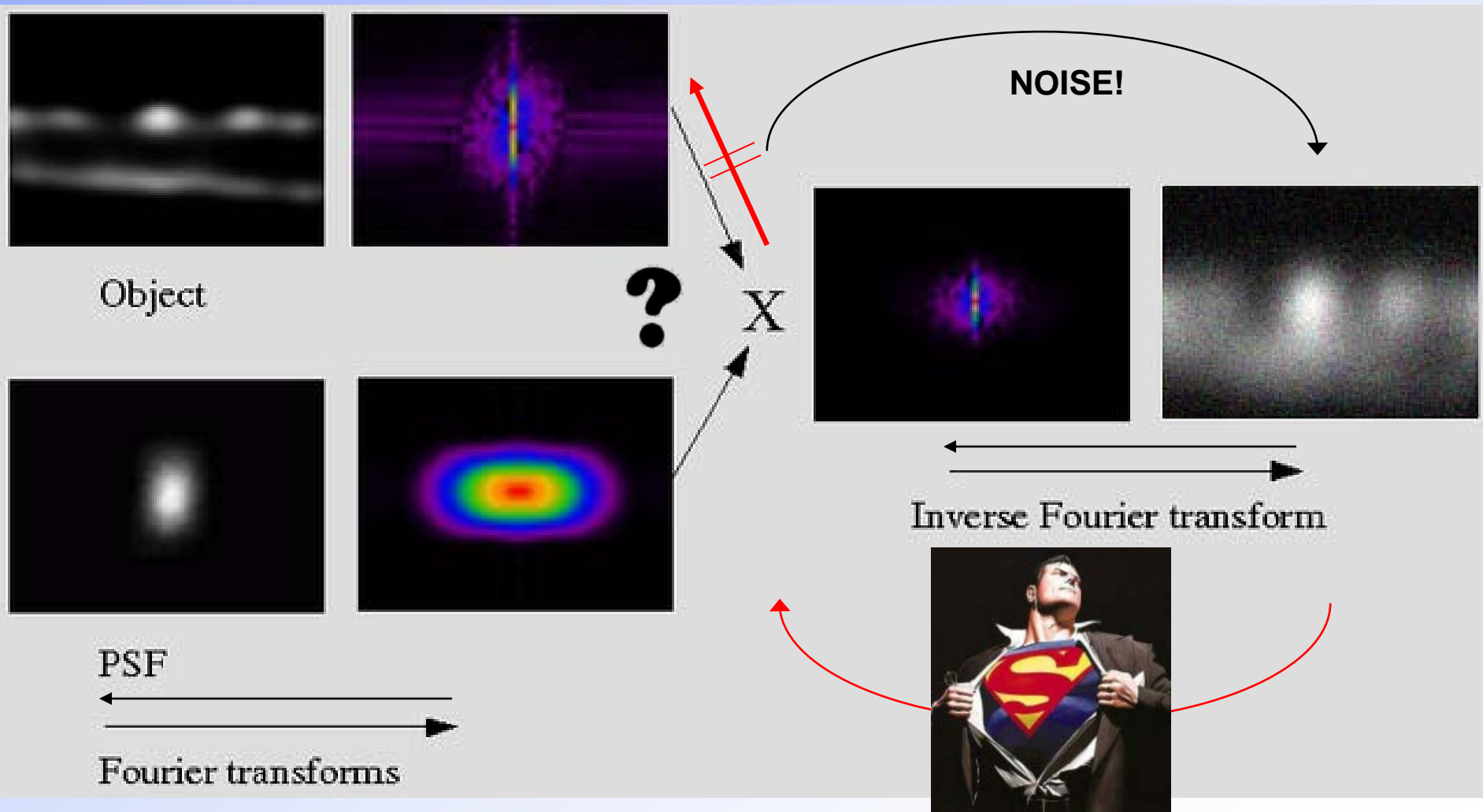
Is de-convolution simply convolution in reverse?

→ **Linear deconvolution** enhances high frequencies.

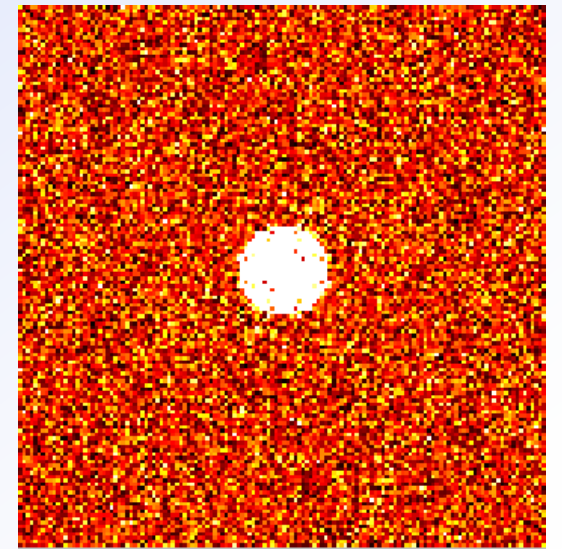
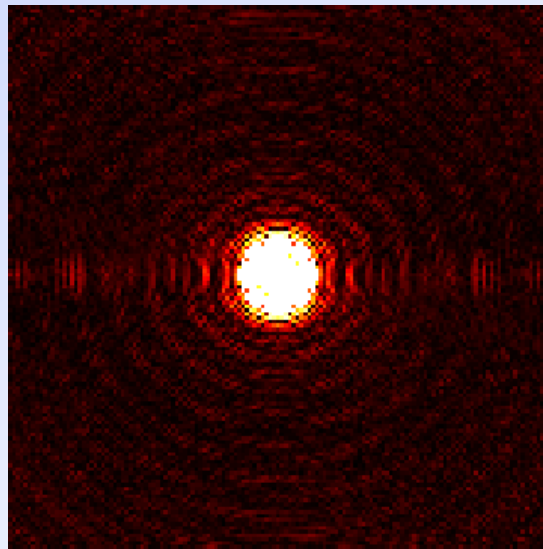
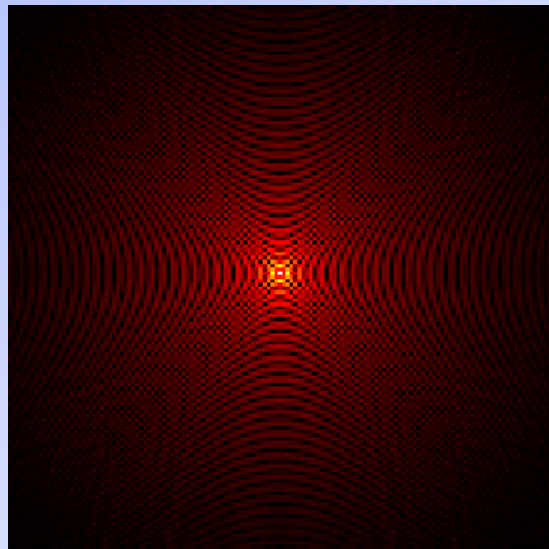
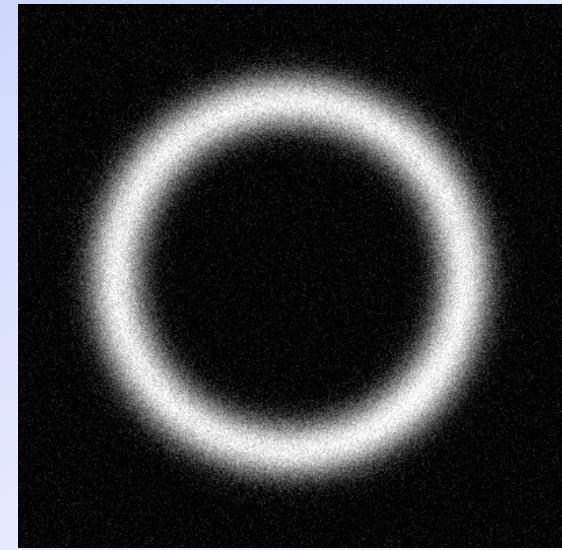
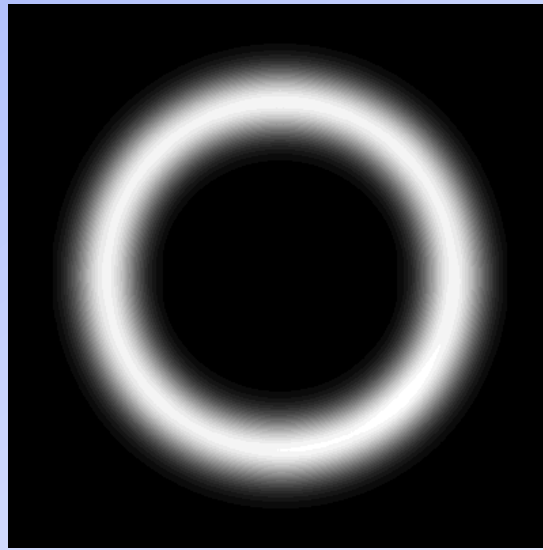
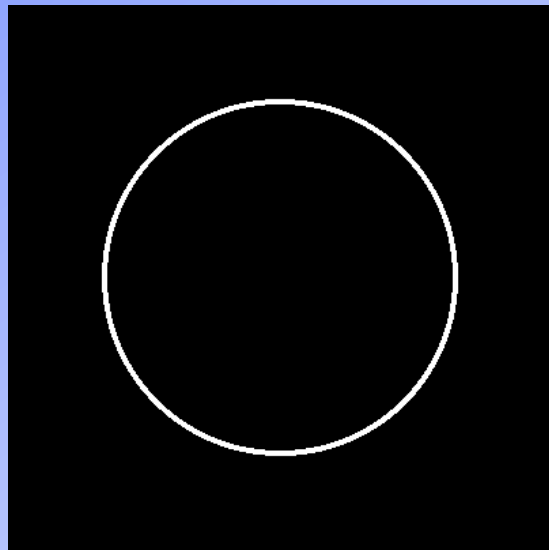


Convolution in frequency space: linear deconvolution

If noise dominates the high frequencies, enhancement creates artifacts.  
Wiener filtering can reduce noise amplification (noise info required).

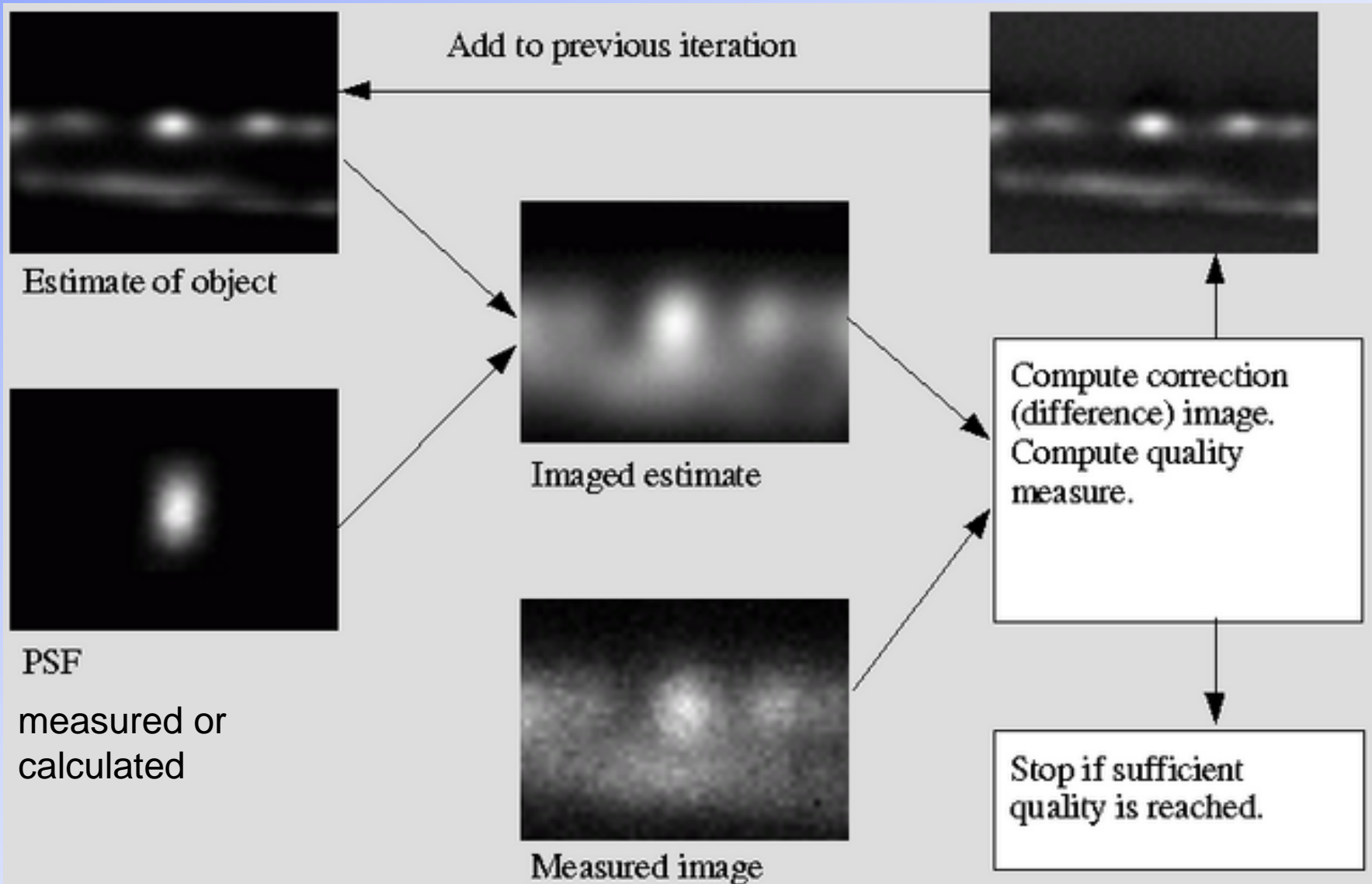


# Object, image and noisy image in position space and frequency space



- High frequencies ( $\rightarrow$  fine details) are attenuated at image acquisition.
- Noise is present at all frequencies.
- The inversion problem: With increasing frequency, the SNR decreases. Reversing convolution can boost high frequency noise to the signal level or higher.

Iterative deconvolution: classical maximum likelihood estimation (CMLE)





The solution: Regularisation and a quality measure

- The iterative process does not converge, because the noise is not an effect of convolution and thus cannot be reflected in the estimate.
- When stoped, the result will contain sub-diffraction artifacts.
- A regularisation parameter forces the estimate to be smooth. With low SNR images, regularisation has to be stronger.
- The quality measure stops the process as soon as the difference between convolved estimate and acquired image is satisfactory.
- Constraints such as non-negativity increase the output image resolution

Function to be minimized:  $[(\text{conv.est} - \text{image}) - \alpha]$

$\alpha$  = regularisation parameter

## Assumptions and pitfalls

1. Avoid undersampling! Images that have not been recorded according to the Nyquist-criterion benefit less from deconvolution, or not at all. This is especially true for a too large step size.

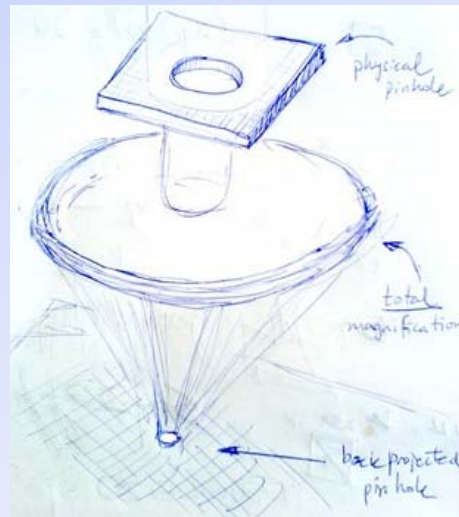
# The Nyquist criterion

- The sampling rate has to be at least twice as fine as the optical resolving power.
- This makes image reconstruction possible, but finer sampling is still better.

Microscope type	<input checked="" type="radio"/> confocal <input type="radio"/> widefield <input type="radio"/> nipkow <input type="radio"/> 4Pi	Select one
Numerical aperture	<input type="text" value="1.3"/>	
Excitation wavelength	<input type="text" value="488"/>	(nm)
Emission wavelength	<input type="text" value="520"/>	(nm)
Number of excitation photons	<input type="text" value="1"/>	
Lens medium refractive index	<input type="text" value="1.515"/>	

☐ Calculate also [PSF](#) with the following extra parameters:

Specimen medium refractive index	<input type="text" value="1.45"/>	
Acquisition depth	<input type="text" value="0"/>	(μm)
Backprojected pinhole radius	<input type="text" value="250"/>	Only for confocal or spinning disks (nm)
B.P. distance between pinholes	<input type="text" value="2.53"/>	Only for spinning disks (μm)



Huygens:  
Nyquist-Calculator  
(<http://www.svi.nl/NyquistCalculator>)

## Zeiss LSM710

This is part of the [Backprojected Pinhole Calculator](#).

### Details

The microscope reports the **side** length (*s*) of a **square** pinhole in microns (μm). Use this reported value in the form below.

Because of the square pinhole, the shape factor is  $c = 1/\sqrt{\pi} \approx 0.5642$ . The system magnification is reported to be 1.9048. The simplified equation to calculate the **Back Projected Pinhole Radius** in nanometers is therefore  $r_b \approx 564s / (1.9048m_{obj})$ .

### Calculator

Pinhole side (microns)	<input type="text"/>
Objective magnification	<input type="text" value="100"/>
<input type="button" value="Calculate"/>	

## Assumptions and pitfalls

1. Avoid undersampling! Images that have not been recorded according to the Nyquist-criterion benefit less from deconvolution, or not at all. This is especially true for a too large step size.
2. Image acquisition has to include all relevant data! Clipping of images, especially along the z-axis, results in loss of information. Detector saturation has to be avoided.
3. The PSF should be invariant to translation (perfect flatness-of-field, no refractive index mismatch). Calculated PSFs can be adapted to continuous deformation along the z-axis..
4. Measured PSFs should ideally be recorded right before image acquisition, at +/- the same conditions.